

Description

The XPX8P10XS uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

 $V_{DS} = -100V I_{D} = -8A$

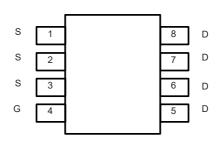
 $R_{DS(ON)} < -83m\Omega$ @ $V_{GS}=-10V$

Application

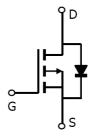
Battery protection

Load switch

Uninterruptible power supply







Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)	
XPX8P10XS	SOP-8	XPX8P10XS XXX YYYY	3000	

Absolute Maximum Ratings (T_C=25°Cunless otherwise noted)

Symbol	Parameter	Rating	Units
V _D s	Drain-Source Voltage	-100	V
V _{GS} Gate-Source Voltage		±20	V
I _D @T _C =25□ Continuous Drain Current, V _{GS} @ -10V ¹		-8	А
I _D @T _C =100□	I _D @T _C =100□ Continuous Drain Current, V _{GS} @ -10V¹		Α
Ідм	Pulsed Drain Current ²	-18	Α
EAS	EAS Single Pulse Avalanche Energy³		mJ
las Avalanche Current		3.1	Α
P _D @T _C =25°C	Total Power Dissipation⁴	3.1	W
Тѕтс	Storage Temperature Range	-55 to 150	℃
T _J Operating Junction Temperature Range		-55 to 150	°C
Reja	R ₀ JA Thermal Resistance Junction-Ambient ¹		°C/W
R _B JC Thermal Resistance Junction-Case ¹		16	°C/W



Electrical Characteristics (T_J=25°C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit	
BVDSS	Drain-Source Breakdown Voltage	e V _{GS} =0V , I _D =-250uA		-110		V	
_	Static Drain-Source On-Resistance ²	V _{GS} =-10V , I _D =- 6A		83	110	mΩ	
Rds(on)		V _{GS} =-4.5V , I _D =-3A		95	120		
V _{GS(th)}	Gate Threshold Voltage	$V_{GS}=V_{DS}$, $I_D=-250uA$	-1.2	-1.8	-2.5	V	
IDSS	Drain-Source Leakage Current	V _{DS} =-100V , V _{GS} =0V , T _J =25℃			-50	uA	
Igss	Gate-Source Leakage Current	V_{GS} =±20 V , V_{DS} =0 V			±100	nA	
gfs	Forward Transconductance	V _{DS} =-10V , I _D =-10A		24		S	
Qg	Total Gate Charge			20.1		nC	
Qgs	Gate-Source Charge	V _{DS} =-50V , V _{GS} =-10V , I _D =-20A		3.9			
Qgd	Gate-Drain Charge			4.3			
Td(on)	Turn-On Delay Time			10			
Tr	Rise Time	V_{DD} =-50V , V_{GS} =-10V , R_{G} =3.3 ,		30		ns	
T _{d(off)}	Turn-Off Delay Time	I _D =-10A		77			
Tf	Fall Time	- ID==10/(81			
Ciss	Input Capacitance			1051			
Coss	Output Capacitance	V _{DS} =-20V , V _{GS} =0V , f=1MHz		119		pF	
Crss	Reverse Transfer Capacitance			25			
ls	Continuous Source Current ^{1,5}	V _G =V _D =0V , Force Current			-15	Α	
VsD	Diode Forward Voltage ²	V _{GS} =0V , I _S =-1A , T _J =25℃			-1.2	V	
trr	Reverse Recovery Time	I=-8A , di/dt=-100A/μs ,		81		nS	
Qrr	Reverse Recovery Charge	Tյ=25°C		140		nC	

Notes:

- 1、Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature
- 2. The test condition is, VDD=80V,VG=10V RG =25 Ω , L=0.1mH.
- 3、The data tested by pulsed Pulse Test: Pulse Width≤300µs, Duty Cycle≤0.5%
- 4. The power dissipation is limited by 150 $^{\circ}$ C junction temperature



Typical Characteristics

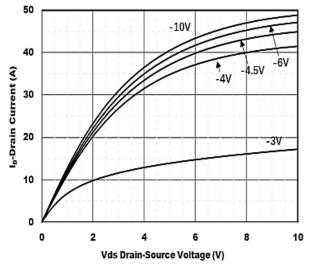


Figure 1. Output Characteristics

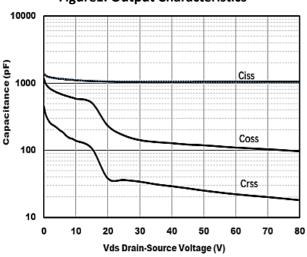


Figure 3. Capacitance Characteristics

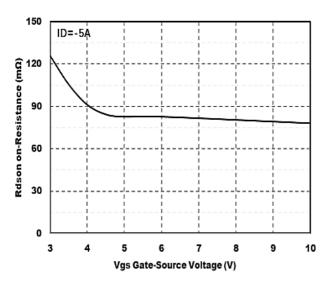


Figure 5. : On-Resistance vs. Gate to Source Voltage

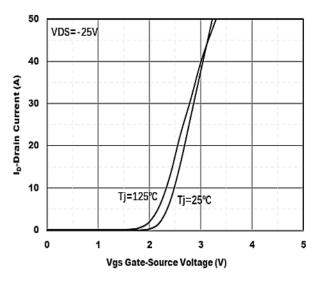


Figure 2. Transfer Characteristics

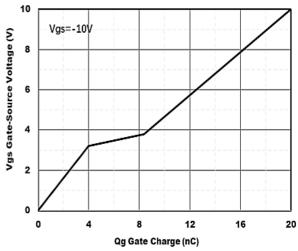


Figure 4. Gate Charge

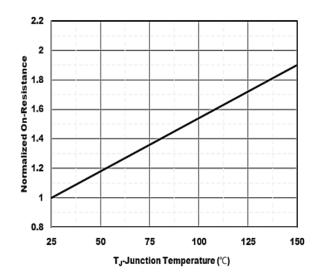
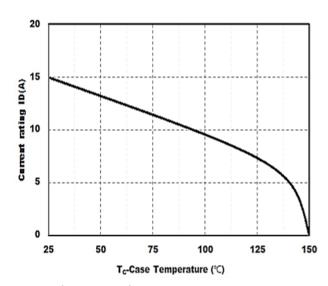


Figure 6. Normalized On-Resistance





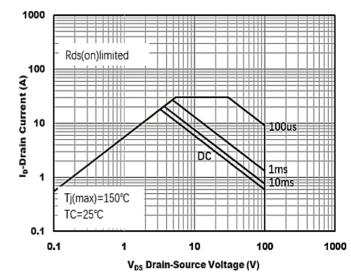


Figure 7. Drain current

Figure8.Safe Operation Area

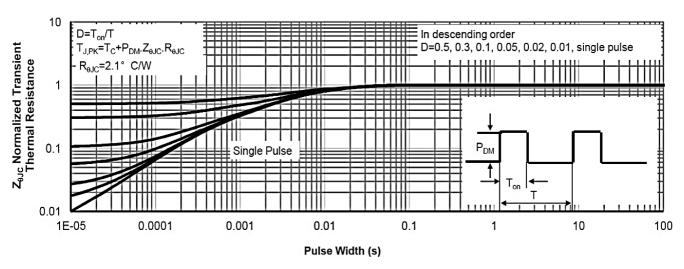


Figure 9. Normalized Maximum Transient thermal impedance

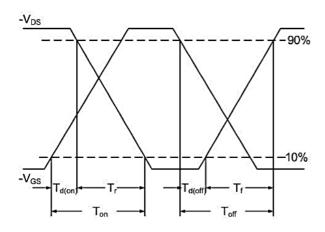


Figure 10 Switching Time Waveform

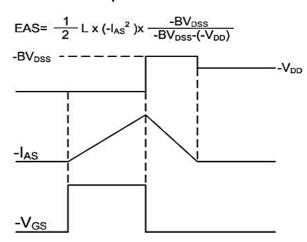
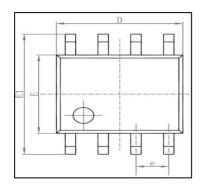
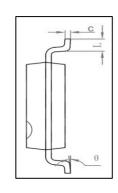


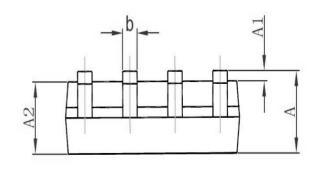
Figure11 Unclamped Inductive Waveform



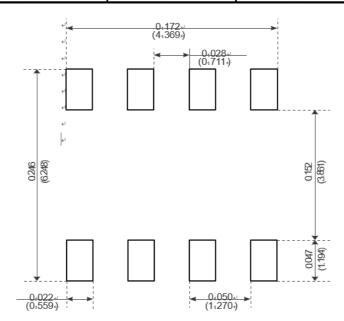
Package Mechanical Data-SOP-8







Cl	Dimensions In	n Millimeters	Dimensions	In Inches
Symbol	Min	Max	Min	Max
Α	1. 350	1. 750	0. 053	0.069
A1	0. 100	0. 250	0. 004	0. 010
A2	1. 350	1. 550	0. 053	0. 061
b	0. 330	0. 510	0. 013	0. 020
С	0. 170	0. 250	0.006	0. 010
D	4. 700	5. 100	0. 185	0. 200
E	3.800	4. 000	0. 150	0. 157
E1	5. 800	6. 200	0. 228	0. 244
е	1. 270 (BSC)		0. 050 (BSC)	
L	0. 400	1. 270	0. 016	0.050
θ	0°	8°	0°	8°



Recommended Minimum Pads-



Flow (wave) soldering (solder dipping)

Product	Peak Temperature	Dipping Time
Pb device	245 ℃ ±5 ℃	5sec±1sec
Pb-Free device	260℃+0/-5℃	5sec±1sec



This integrated circuit can be damaged by ESD UniverChip Corporation recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedure can cause damage. ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

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